

VLSI Testing

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- **Analog Testing**

References

1. **Digital System Testing and Testable Design, 1990, By M. Abramovici, M.A. Breuer & A.D. Friedman.**
2. **Logic Testing and Design for Testability, 1985, By Hideo Fujiwara.**
3. **Proceedings in ≥ 30 Conferences/Symposiums/Workshops supported by IEEE each year.**
4. **International Journals: IEEE T-CAD, T-VLSI, T-C&S, T-Computers, JETTA, etc.**

Class Requirements & Grading

- **Homeworks** **15%**
- **6 Exercises** **30%**
- **One Midterm Exam** **25%**
- **One Final Exam** **30%**

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WWW 網站:

http://140.116.156.89/~KJLee/moe/testing_course/